

**Search Notes**

Application/Control No.

10/765,565

Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	1/17/2007	DX
455	414.1	1/17/2007	DX

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass Search	1/17/2006	AX
Combined Text search	1/17/2006	CH